Surface-induced resistivity of gold films on mica: Comparison between the classical and the quantum theory

Munoz, Raúl C.

Vidal, Guillermo

Kremer, Germán

Moraga, Luis

Arenas, Claudio

We report an extension of the theory of Sheng, Xing and Wang (SXW) (Sheng L, Xing D Y and Wang Z D 1995 Phys. Rev. B 51 7325), which permits the calculation of size effects from the statistical properties that characterize the surface on a microscopic scale, for samples in which the average height-height autocorrelation function (ACF) is described either by a Gaussian or by an exponential. We also report measurements of the topography of a gold film deposited on a mica substrate using a scanning tunnelling microscope (STM) on a gold sample 70 nm thick deposited under ultrahigh vacuum on a mica substrate preheated to 300°C. From the STM images we compute the average ACF which characterizes the surface of the film on the scale of 10 nm × 10 nm, and determine by least-squares fitting the r.m.s. amplitude? and the lateral correlation length? corresponding to a Gaussian and to an exponential that best represent the ACF data. Using the modified SXW (mSXW) theory and a Gaussian and an exponential